Mart Coenen, EMCMCC, Eindhoven, the Netherlands Arthur van Roermund, Eindhoven University of Technology Mixed-signal Microelectronics, Eindhoven, the Netherlands mart.coenen@emcmcc.nl, a.h.m.v.roermund@tue.nl







Presentation outline

- Introduction
- Overview
- New approach
- Conclusions



EMC MCC ≥

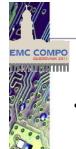




Introduction

- With nanometre scaling, the amount of transistors/chip will follow Moore's Law.
- On- and off-chip clock and data speeds will increase further.
- Core supply voltages are reduced further down to below 1 Volt
- Peripheral supply voltages have to follow international agreed voltages levels to enable interfacing.







- While lowering the core supply voltages, the on-chip noise margin will drop accordingly
- Tight on- and off-chip decoupling measures are necessary.
- Typically, RF switching noise from digital designs are forced out of their packages through the supply and ground pins when applying conventional off-chip decoupling





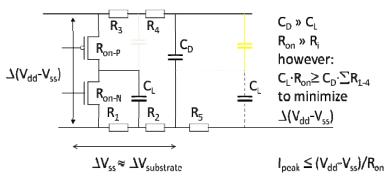
Overview of measures

- On-chip measures
 - On-chip decoupling; needed for operation
 - Spread-spectrum; spreading in frequency domain
 - Multi-phase clocking; spreading in time domain
 - Embedded LDO; current confinement
 - Variable voltage, variable frequency
- Off-chip measures
 - Kelvin contacts
 - Complementary off-chip measures
 - Resonance free PDN design





Overview (of what has been done)



- Supply bounce; IR-drop and delay
- V_{ss}-net/substrate analysis

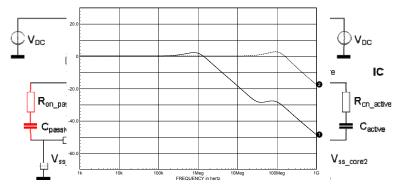


EMC MCC



EMC MCC &

Overview (of what has been done)



Current confinement by Kelvin contacts for Off-chip decoupling







New approach

- On-chip decoupling is always present: μC , DSP, FPGA, etc. both for core and peripherals
- Equivalent package induction with on-chip capacitance is at resonance below 100 MHz: example: 200 nF + 0,2 nH → ~25 MHz
- When ideally decoupled <u>off-chip</u> quality factor of resonance > 10 is reached
- Need for dampening !! (in example just 31 m Ω !!)







New approach

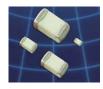
- Multiple decoupling capacitors are root cause for resonances. Values: 1:10:100:1000 are typ. placed in parallel to cover whole frequency range. ESL and physical distance add inductances thus resonances
- Multiple supply/ground planes in parallel in a multilayer PCB structure are additional root cause for resonances. Open and shortcircuited TL-ends cause steep resonances from several MHz into GHz range

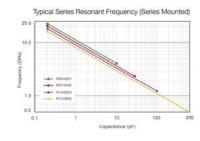


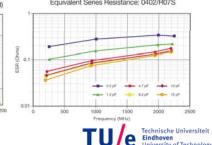




 Ceramic multilayer capacitors have resonance frequency in GHz range with Q > 1000, larger capacitance → lower ESR





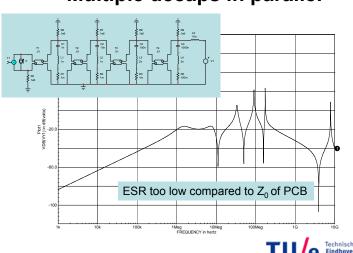


EMC MCC



EMC MCC ≧√

Multiple decaps in parallel







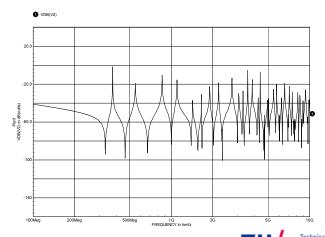
- Inter-plane characteristic impedance is between 0,1 and 2,5 Ω . Multiple plane pairs can be used in parallel
- Port impedance is $Z_0/4$ as signals are propagation to all 4 edges or when rotation symmetric diverging; $Z_0/2\pi$
- Port impedances less than 10 m Ω easy achievable; 3 plane pairs at 100 μm spacing







Off-center port on Euro-card, $Z_0 = 10 \text{ m}\Omega$







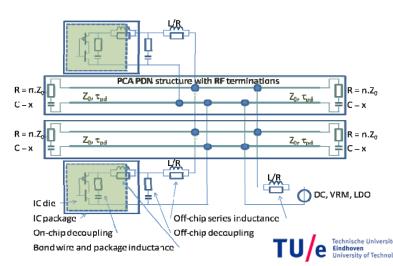
New approach

- The whole PDN chain from DC supply to the IC supply pads needs to be considered
- All "taps" and "feeds" shall:
 - impedance » $Z_0/4$ ≥ f_{crit}
 - resonant free; Q ≤ 2
- · Due to skin and proximity effects full insulation between supply/ground currents and signal return paths are achieved skin depth = 6 μ m @ 100 MHz, Cu-layer = 37 μ m





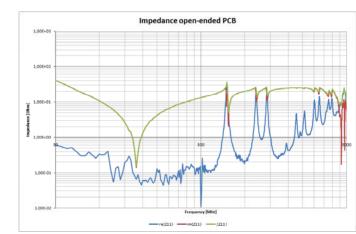
Total Resonant-Free PDN solution







Device port impedance Z₁₁

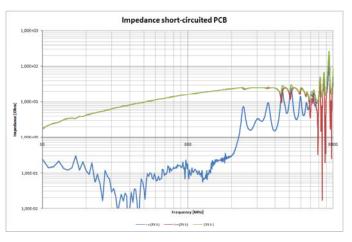








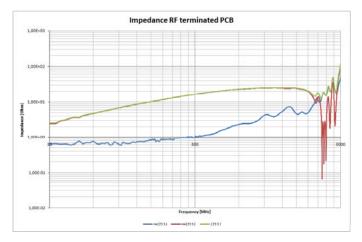
Device port impedance Z_{11}







Device port impedance Z₁₁







Conclusions

- Each part of the PDN chain shall be optimally dampened, by using: series inductance + series resistance or Kelvin contacts
- Decoupling capacitors shall be optimised for ESR too, ESL remains less critical
- Off-chip decoupling, through short PDNs, is too late for decoupling in the sub-ns region (due to self-resonance (skew) and delay of the device's PDN and in its package)
- Resonant-Free PDN is an option.



